

Search Notes

Application/Control No.

10/700,919

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

NAFFZIGER ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
341	135		
	136		
326	82		
	83		
327	403		
	404		
	427		
323	315	12/05	gA

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner